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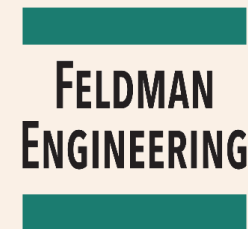
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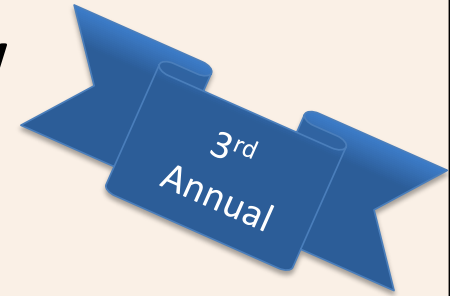
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BiTS China Overview



Welcome to the BiTS China Workshop!

- **Burn-in and Test Strategies Workshop**
- A scope that incorporates next-generation solutions to test and burn-in challenges while also providing vital, current information on traditional technologies

What's NOW & NEXT in Test and Burn-in of Semiconductors

- The World's Premier Forum For The Latest Information
- Extensive & Diverse Technical Program
- The Latest Products & Services at BiTS China EXPO
- Networking Opportunities

Feedback & Suggestions are Encouraged

Informal and Casual Throughout All Sessions & Activities

Core Values

What's *Now & Next* in Burn-in and Test

Premier Event ♦ Cutting Edge ♦ Staying Ahead

Learn...

Technical Program

Explore...

BiTS EXPO – 17 Exhibitors

...Share

Networking Opportunities

Learn ...

Podium Sessions

- 2 Sessions
- 9 Practical & Useful Technical Presentations

Renowned Speakers

- Keynote Address
- Marketplace Report

BiTS Tutorial

- Learn From Industry Experts & Build Your Leading Edge Skills

... Explore ...

BiTS EXPO

- 17 Companies Are Exhibiting
- Exhibits Area is Open
 - Thursday 12:30 – 18:00
- Lucky Draw at 17:45
 - Must be present

... Share

Meet and Chat With Someone You Don't Know!

- Opportunities to Network, Share & Discuss Ideas
 - Over Lunch or Afternoon Tea

BiTS China Awards Best Presentation

China
2016

"Study of Probe Pin Internal Resistance"
"弹簧探针内部阻值的研究"

Takuto Yoshida - Test Tooling Solutions Group

China
2015

"LPDDR4 Signal & Power Performance Optimization By Hardware"
"通过测试硬件的优化来提升LPDDR4信号和电源的性能"

Yuanjun Shi - Twinsolution Technology
Xiao Yao - HiSilicon Technologies Co

E-Proceedings

<http://bitstestworkshop.org/proceedings>

Password: Huangpu17

Workshop Guide

<http://bitstestworkshop.org/guide>

bitstestworkshop.org

Your Complete Source For Information About BiTS

Current Workshop

- Call For Papers
- EXPO & Sponsorships
- Advance/Final Program
- Registration Information & Forms; Register On-line
- Author Information
- Hotel Information/Travel

Features

- Committee Members
- Contact BiTS - Add to Mailing List & Inquiries
- Links to Other Websites
- 'Press' About BiTS
- Archive of past BiTS
- Search BiTS Feature

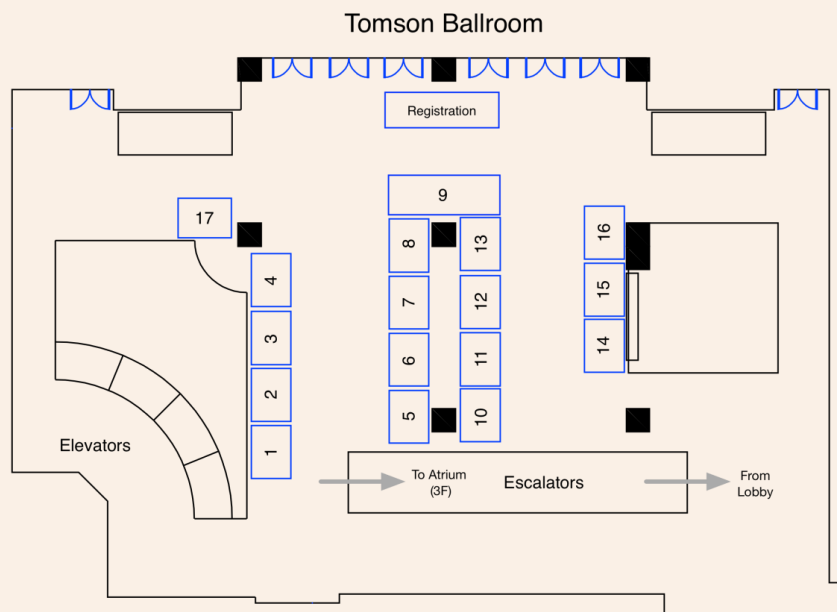
Plus Premium Archive...

BiTS Premium Archive

- Multimedia
 - Audio with synchronized slides & pointer
 - BiTS 2013 thru BiTS 2017
 - BiTS China (Shanghai) 2015 & BiTS China 2016
 - BiTS China 2017 posted shortly after BiTS China
- Additional content
 - Tutorials
- Subscription Model
 - BiTS Professional Attendees – Full Subscription for 1 Year
 - BiTS China Attendees – Access to China content for 1 Year
 - Subscriber – Nominal Fee
 - Applied to BiTS 2017 Registration

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BiTS China EXPO



Exhibitor	Booth
Chip Shine	6
Cohu	11
Foxconn Interconnect Technology	2
HiCon	3
ISC Co., Ltd.	16
IWIN Co., Ltd.	12
JDT	15
Leeno Industrial, Inc.	4
Polymics' Ltd	14
Nitaku Electronics Technology	17
Sensata Technologies, Inc.	13
Smiths Interconnect	7
Test Tooling Solutions Group	9
TSE Co., Ltd.	10
WinWay Technology	8
Xcerra Coporation	5
Zenfocus	1

BiTS China

9:00 **Opening Remarks & Keynote**
Ira Feldman – BiTS Workshop General Chair
Steven Zheng – BiTS China Workshop Chair
Tingyu Lin – Keynote “Fan Out Technology Overview”

10:00 **Market Report**
Lin Fu - Opportunities and Challenges of the Chinese Test and Burn-in Sockets Market

10:30 **Networking & Refreshment Break**

11:00 **Session 1 - RF & High Speed Test**
Radio frequency and high speed test challenges

12:00 **Lunch & BiTS EXPO Opens** (BiTS EXPO opens at 12:30)

BiTS China

- | | |
|-------|--|
| 13:30 | Session 1 Continued – RF & High Speed Test
<i>Radio frequency and high speed test challenges</i> |
| 14:30 | BiTS EXPO Continues & Afternoon Tea |
| 15:00 | Session 2 - SiP Test & Contact Technology
<i>Latest presentations on challenges of SiP test and contact technology</i> |
| 17:45 | Lucky Draw / Door Prizes |
| 18:00 | BiTS China Adjourn |

Opening Remarks

BiTS China

Opening Remarks

Ira Feldman

General Chair,
BiTS Workshop

Steven Zheng

BiTS China Chair

Call for BiTS 2018

March 4-7, 2018 ♦ Mesa, Arizona

Presentations ♦ Posters ♦ Tutorial

BiTS EXPO 2018 & Sponsors

Share your latest work and advancements as an **AUTHOR!** Your presentation or poster will be part of a stimulating and comprehensive program. Explore a demanding topic as a **TUTORIAL INSTRUCTOR.** Share your expertise with participants eager to build their leading edge skills. Presentation, Poster & Tutorial proposals addressing a broad range of burn-in and test subjects are welcome, including, but not limited to:

- Socketing/Contacting of Contemporary and Advanced Packaging Technologies
- PCBs, Materials, Handlers, Contact Technologies, Burn-in Tooling
- Modeling, Characterization & Analysis
- Process & Operational Challenges
- WLCSP Test for KGD or Final Test
- MEMS and Non-Electrical Stimuli Test

The **EVENT** for exhibiting your company's products & services. Showcase and promote what is **Now & Next!**

Don't miss out! See the registration desk to sign up now at the early-bird discount rate. **BiTS EXPO** is sure to sell out!

For more information about BiTS 2018 please contact the BITS Office
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Keynote
Address

BiTS Workshop 2017 Schedule

BiTS China

Thursday September 7 - 9:15 am

Fan Out Technology Overview

Tingyu Lin

National Centre for Advanced Packaging (NCAP), China

Market
Report

BiTS China

Opportunities and Challenges of the Chinese Test
and Burn-in Sockets Market

Lin Fu & John West

VLSI Research Europe

BiTS China

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Session 1

Frank Zhou
Session Chair

BiTS Workshop 2017 Schedule

BiTS China

RF & High Speed Test

"High Speed Testing"

Jackie Luo - Shanghai Zenfocus Semi-Tech Co., Ltd

"Flat Probe Technology for RF Test"

Dongmei Han - Xcerra

"Coplanar Waveguide On Wafer Calibration Technology for Enabling High Volume Microwave On-Wafer Test"

Yuzhe Yin - China Electronics Standardization Institute

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Radio frequency and high speed test challenges

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15:00 Session 2 - **SiP Test & Contact Technology**
Latest presentations on challenges of SiP test and contact technology

17:45 Lucky Draw / Door Prizes

18:00 BiTS China Adjourn

Session 1

Frank Zhou
Session Chair

BiTS Workshop 2017 Schedule

BiTS China

RF & High Speed Test

"DUT ATE Test Fixture S-Parameters Estimation using 1x-Reflect Methodology"

Jose Moreira - Advantest

"Contactor Arcing Fundamentals"

Yoinjun Shi – TwinSolution

BiTS China

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Session 2

Yoinjun Shi
Session Chair

BiTS Workshop 2017 Schedule

BiTS China

SiP Test & Contact Technology

"The challenge of testing and burn-in for System in Package"

Leo Wang - ISE Labs, member of ASE Group

"Socket Material Characterization & Selection"

Jinrong "Cleveland" Chen - Smiths Interconnect

"Deterministic contact resistance of BGA contact pins"

Terry Wang - Infineon

"New universal multi-beam Kelvin contactor concept for turret applications"

Mathias Westenhuber - Cohu

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BiTS China

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Awards &
Closing

BiTS China

Awards & Closing Remarks

Ira Feldman
General Chair,
BiTS Workshop